### N-Channel Enhancement Mode Power MOSFET

#### **DESCRIPTION**

The HM1404 $\hat{O}$  uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

#### **GENERAL FEATURES**

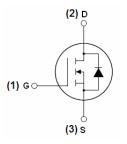
- $V_{DS} = 40V, I_D = 170A$  $R_{DS(ON)} < 3.7mΩ @ V_{GS} = 10V$  (Typ:2.7mΩ)
- Special process technology for high ESD capability
- High density cell design for ultra low Rdson
- Fully characterized Avalanche voltage and current
- Good stability and uniformity with high E<sub>AS</sub>
- Excellent package for good heat dissipation

#### **Application**

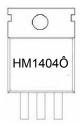
- Power switching application
- Hard Switched and High Frequency Circuits
- Uninterruptible Power Supply

100% UIS TESTED!

100% AVds TESTED!



#### Schematic diagram



Marking and pin Assignment



TO-220-3L top view

#### **Package Marking And Ordering Information**

| Device Marking | Device  | Device Package | Reel Size | Tape width | Quantity |
|----------------|---------|----------------|-----------|------------|----------|
| HM1404C        | HM1404C | TO-220-3L      | -         | -          | -        |

# Absolute Maximum Ratings (TC=25℃unless otherwise noted)

| Parameter                                       | Symbol                | Limit | Unit |
|---|-----------------------|-------|------|
| Drain-Source Voltage                            | V <sub>DS</sub>       | 40    | V    |
| Gate-Source Voltage                             | V <sub>G</sub> s      | ±20   | V    |
| Drain Current-Continuous                        | I <sub>D</sub>        | 170   | А    |
| Drain Current-Continuous(T <sub>C</sub> =100°C) | I <sub>D</sub> (100℃) | 119   | Α    |
| Pulsed Drain Current                            | I <sub>DM</sub>       | 510   | Α    |
| Maximum Power Dissipation                       | P <sub>D</sub>        | 260   | W    |



| Derating factor                                  |                 | 1.73       | W/°C       |
|--|-----------------|------------|------------|
| Single pulse avalanche energy (Note 5)           | E <sub>AS</sub> | 1500       | mJ         |
| Operating Junction and Storage Temperature Range | $T_J, T_{STG}$  | -55 To 175 | $^{\circ}$ |

#### **Thermal Characteristic**

| Thermal Resistance, Junction-to-Case (Note 2) | $R_{	heta Jc}$ | 0.58 | °C/W |
|---|----------------|------|------|
|---|----------------|------|------|

## Electrical Characteristics (TC=25°Cunless otherwise noted)

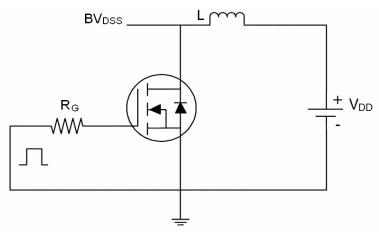
| Parameter                          | Symbol              | Condition  | Min | Тур  | Max  | Unit |
|------------------------------------|---------------------|--|-----|------|------|------|
| Off Characteristics                |                     |  | •   |      |      |      |
| Drain-Source Breakdown Voltage     | BV <sub>DSS</sub>   | V <sub>GS</sub> =0V I <sub>D</sub> =250μA                            | 40  | -    | -    | V    |
| Zero Gate Voltage Drain Current    | I <sub>DSS</sub>    | V <sub>DS</sub> =40V,V <sub>GS</sub> =0V                             | -   | -    | 1    | μA   |
| Gate-Body Leakage Current          | I <sub>GSS</sub>    | V <sub>GS</sub> =±20V,V <sub>DS</sub> =0V                            | -   | -    | ±100 | nA   |
| On Characteristics (Note 3)        |                     |  |     |      |      |      |
| Gate Threshold Voltage             | V <sub>GS(th)</sub> | V <sub>DS</sub> =V <sub>GS</sub> ,I <sub>D</sub> =250μA              | 2   | 3    | 4    | V    |
| Drain-Source On-State Resistance   | R <sub>DS(ON)</sub> | V <sub>GS</sub> =10V, I <sub>D</sub> =40A                            | +   | 2.7  | 3.7  | mΩ   |
| Forward Transconductance           | <b>g</b> FS         | V <sub>DS</sub> =5V,I <sub>D</sub> =40A                              | 60  | -    | -    | S    |
| Dynamic Characteristics (Note4)    |                     |  | •   |      |      |      |
| Input Capacitance                  | C <sub>lss</sub>    | \/ -20\/\/ -0\/  | -   | 9000 | -    | PF   |
| Output Capacitance                 | C <sub>oss</sub>    | $V_{DS}$ =30V, $V_{GS}$ =0V,<br>F=1.0MHz                             | -   | 880  | -    | PF   |
| Reverse Transfer Capacitance       | C <sub>rss</sub>    | F=1.0IVID2   | -   | 520  | -    | PF   |
| Switching Characteristics (Note 4) |                     |  |     |      |      |      |
| Turn-on Delay Time                 | t <sub>d(on)</sub>  |  | -   | 21   | -    | nS   |
| Turn-on Rise Time                  | t <sub>r</sub>      | $V_{DD}$ =30 $V$ , $I_{D}$ =1 $A$                                    | -   | 37   | -    | nS   |
| Turn-Off Delay Time                | t <sub>d(off)</sub> | $V_{GS}$ =10 $V$ , $R_{GEN}$ =2.5 $\Omega$                           | -   | 75   | -    | nS   |
| Turn-Off Fall Time                 | t <sub>f</sub>      |  | -   | 40   | -    | nS   |
| Total Gate Charge                  | Qg                  | \/ -20\/   -20 \   | -   | 170  | -    | nC   |
| Gate-Source Charge                 | Q <sub>gs</sub>     | $V_{DS}=30V,I_{D}=30A,$<br>$V_{GS}=10V$                              | -   | 36   | -    | nC   |
| Gate-Drain Charge                  | $Q_{gd}$            | VGS=10V  | -   | 56   | -    | nC   |
| Drain-Source Diode Characteristics |                     |  |     |      |      |      |
| Diode Forward Voltage (Note 3)     | V <sub>SD</sub>     | V <sub>GS</sub> =0V,I <sub>S</sub> =20A                              | -   | -    | 1.2  | V    |
| Diode Forward Current (Note 2)     | Is                  | -  | -   | -    | 170  | Α    |
| Reverse Recovery Time              | t <sub>rr</sub>     | TJ = 25°C, IF = 40A  | -   | 47.5 | -    | nS   |
| Reverse Recovery Charge            | Qrr                 | di/dt = 100A/μs(Note3)   | -   | 66.3 | -    | nC   |
| Forward Turn-On Time               | t <sub>on</sub>     | Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD) |     |      |      |      |

#### Notes:

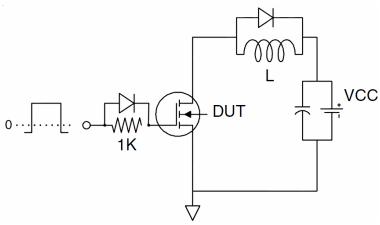
- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- 3. Pulse Test: Pulse Width  $\leq$  300 $\mu$ s, Duty Cycle  $\leq$  2%.
- **4.** Guaranteed by design, not subject to production
- **5.** EAS condition: Tj=25  $^{\circ}\text{C}$  ,VDD=30V,VG=10V,L=0.5mH,Rg=25 $\Omega$

# **Test circuit**

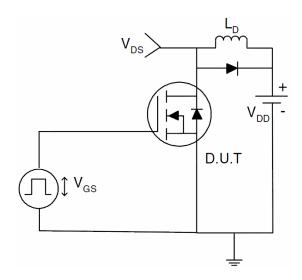
# 1) E<sub>AS</sub> test Circuits



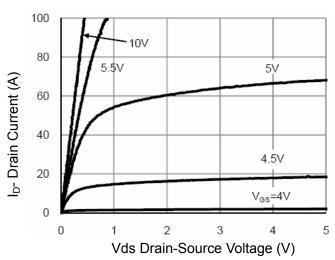
# 2) Gate charge test Circuit:



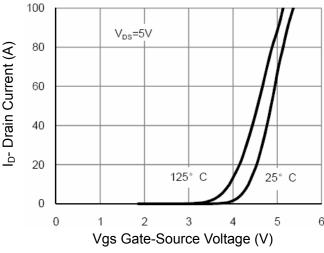
# 3) Switch Time Test Circuit:



# TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS (Curves)



**Figure 1 Output Characteristics** 



**Figure 2 Transfer Characteristics** 

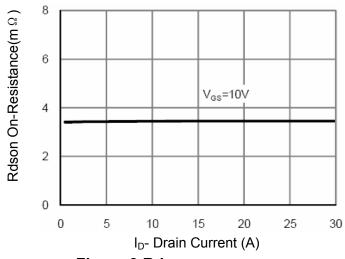


Figure 3 Rdson- Drain Current

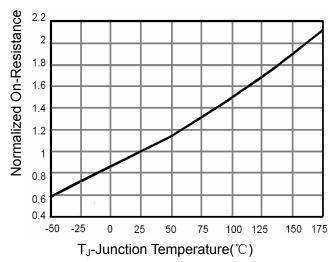


Figure 4 Rdson-JunctionTemperature

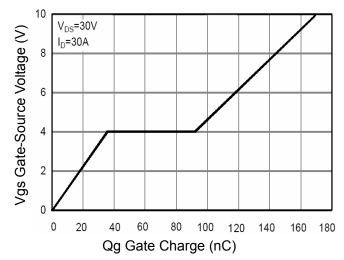


Figure 5 Gate Charge

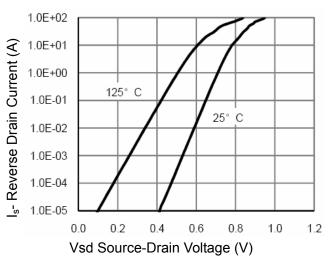


Figure 6 Source- Drain Diode Forward

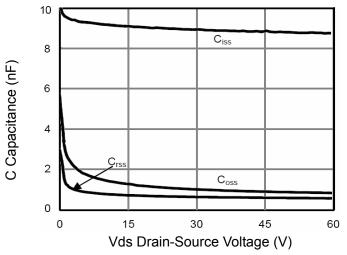
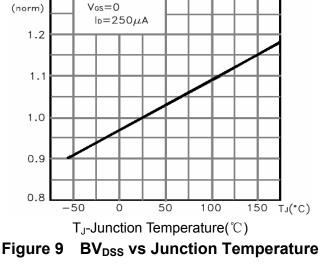


Figure 7 Capacitance vs Vds



 $\mathsf{BV}_{\mathsf{DSS}}$ 

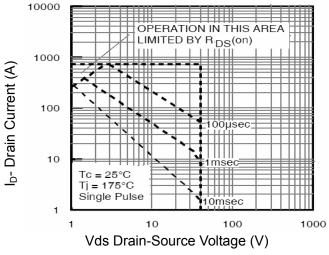


Figure 8 Safe Operation Area

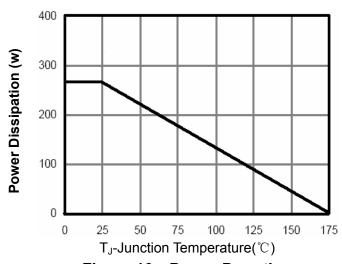
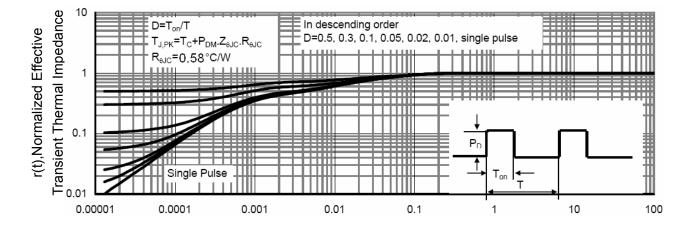


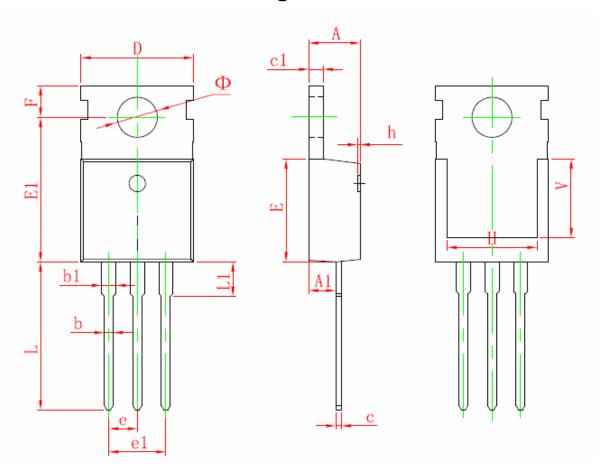
Figure 10 Power De-rating



Square Wave Pluse Duration(sec)

**Figure 11 Normalized Maximum Transient Thermal Impedance** 

# **TO-220-3L Package Information**



| Cumbal | Dimensions | In Millimeters | Dimensions In Inches |       |  |
|--------|------------|----------------|----------------------|-------|--|
| Symbol | Min.       | Max.           | Min.                 | Max.  |  |
| Α      | 4.400      | 4.600          | 0.173                | 0.181 |  |
| A1     | 2.250      | 2.550          | 0.089                | 0.100 |  |
| b      | 0.710      | 0.910          | 0.028                | 0.036 |  |
| b1     | 1.170      | 1.370          | 0.046                | 0.054 |  |
| С      | 0.330      | 0.650          | 0.013                | 0.026 |  |
| c1     | 1.200      | 1.400          | 0.047                | 0.055 |  |
| D      | 9.910      | 10.250         | 0.390                | 0.404 |  |
| E      | 8.950      | 9.750          | 0.352                | 0.384 |  |
| E1     | 12.650     | 2.950          | 0.498                | 0.116 |  |
| е      | 2.540      | TYP.           | 0.100 TYP.           |       |  |
| e1     | 4.980      | 5.180          | 0.196                | 0.204 |  |
| F      | 2.650      | 2.950          | 0.104                | 0.116 |  |
| Н      | 7.900      | 8.100          | 0.311                | 0.319 |  |
| h      | 0.000      | 0.300          | 0.000                | 0.012 |  |
| L      | 12.900     | 13.400         | 0.508                | 0.528 |  |
| L1     | 2.850      | 3.250          | 0.112                | 0.128 |  |
| V      | 7.500      | REF.           | 0.295 REF.           |       |  |
| Φ      | 3.400      | 3.800          | 0.134                | 0.150 |  |



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